A Theoretical Framework for Measuring the Performance of Deep Belief Networks

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In many signal processing applications, the the set A, of signals we wish to recover, as well as the interference set B (usually referred to as "Clutter") are both sparse. This implies that the resulting set X = A + B of recorded signals must be sparse as well. The Detection/Estimation (DE) problem can be seen as a classification problem on this set X.

The work summarized in the present Abstract, illustrates how the *Convolutional Network* (CN, [1]), a successful approach to Supervised Learning, is in fact fundamentally related to the Mathematical Theory of *Compressed Sensing*. We show through a series of experiments that the *Convolutional Network* efficiently approximates the optimal polynomial time algorithm implied in the theory ¹. We present a theoretical foundation for a non probabilistic DE-theory for signals in clutter and argue in favor of the solution of such problems by means of CN-based strategies.

Resting on known results, but only recently starting to attract the efforts of the Scientific Community, Discrete Compressed Sensing ([2]) deals with the task of economically recording information about signals, viewed as a elements of a vector space $\mathcal{V} \simeq \mathbf{R}^N$. More specifically, n non-adaptive measurements $\{y_1, \ldots, y_n\} \in \mathbf{R}$ are made of $x \in \mathcal{V}$. Each measurement takes the form of a linear functional $\Phi_k : \mathcal{V} \to \mathbf{R}$ applied to x:

$$\Phi_k(x) = y_k \tag{1}$$

In general we can write:

$$\Phi = (\Phi_1, \dots, \Phi_n), n \ll N \tag{2}$$

So that, with obvious notation:

$$\Phi: \mathcal{V} \to \mathcal{W}. \tag{3}$$

We can interpret the series of measurements (in a given order) as having made the choice of a *compressive matched filter* ([3]) acting on the space \mathcal{V} to acquire information about the object x.

¹It has been proven that, under the assumption of sparsity of the sets X, such optimal compressive matched filters ([3]) can be found in polynomial time.

Once the information is collected (or "encoded") by means of the matched filters, a non-linear mapping $\Delta_{\Phi}: W \to V$ is formed to reconstruct the original object x, and the error is computed with respect to some norm $N(\cdot) = \|\cdot\|$ of choice. Next we define the error:

$$E(x, \Phi, \Delta_{\Phi}) = \|\Delta_{\Phi}(\Phi(x)) - x\|. \tag{4}$$

The most relevant aspect of the Compressed Sensing framework is that the best possible performance of an encoder-decoder pair can be determined by a simple mathematical bound. In particular, if $X \subset \mathcal{V}$ is a sparse set, the error of Δ_{Φ} on X is the maximum error of any individual reconstruction of X:

$$E(X, \Phi, \Delta_{\Phi}) = \sup_{x} (E(x, \Phi, \Delta_{\Phi})), \qquad (5)$$

and the error of the best decoder is :

$$E(X, N, n) = inf_{\Phi} (E(X, \Phi, \Delta_{\Phi})). \tag{6}$$

It holds that, under reasonable regularity assumptions for X, the best possible decoder is bounded by:

$$d^{n}(X) \le E(X, N, n) \le C \cdot d^{n}(X). \tag{7}$$

where $d^n(X)$ is a number depending on the choice of the norm N called the Gelfand n-width of the set X^2 . In particular, the minimum number M of measurements needed to reconstruct the geometry of X follows the bound:

$$M = C \cdot K \cdot log\left(\frac{N}{K}\right) ([3]) \tag{8}$$

Our works shows that the number of features needed by a CN-classifier follows this growth-law.

References

- [1] Y. LeCun, L. Bottou, Y. Bengio, and P. Haffner, "Gradient-based learning applied to document recognition," *Proceedings of the IEEE*, vol. 86, no. 11, pp. 2278–2324, November 1998.
- [2] David L. Donoho, "Compressed sensing.," *IEEE Transactions on Information Theory*, vol. 52, no. 4, pp. 1289–1306, 2006.
- [3] Michael B. Wakin Mark A. Davenport and Richard G. Baraniuk, "The compressive matched filter," Technical Report TREE 0610, Rice University, Department of Electrical and Computer Engineering, November 2006.

²The Gelfand width of $X \subset \mathcal{V}$ is defined as the $\inf_{Y} \{ \sup(\|x\|) \mid x \in X \cap Y \}$ where Y is a subspace of \mathcal{V} of codimension n